

## Notice of References Cited

Application/Control No.

10/088,790

Examiner

Daniel G. DePumpo

Applicant(s)/Patent Under
Reexamination
FUKUDA ET AL.

Art Unit
Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,590,732 A	01-1997	Sugino et al.	180/444
	В	US-5,921,344 A	07-1999	Boyer, Michael J.	180/444
	С	US-5,971,094 A	10-1999	Joshita, Kaname	180/444
	D	US-4,825,972	05-1989	Shimizu, Yasuo	180/444
	Е	US-5,988,311 A	11-1999	Kuribayashi et al.	180/444
	F	US-6,155,376 A	12-2000	Cheng, Wangquan	180/444
	G	US-6,173,802 B1	01-2001	Kodaira et al.	180/444
	Н	US-6,378,646 B1	04-2002	Bugosh, Mark J.	180/444
	ı	US-6,644,432 B1	11-2003	Yost et al.	180/444
	J	US-6,460,650 B2	10-2002	Tsuboi et al.	180/444
	К	US-6,427,799 B1	08-2002	Kodaira, Tadao	180/444
	Ļ	US-	,		
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	Q					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.